A LOW POWER OPERATIONAL AMPLIFIER DESIGN USING 18NM FIN-FET TECHNOLOGY FOR BIOMEDICAL APPLICATIONS

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ABSTRACT
Bioelectric impedances have been found to correlate with a number of biological phenomena in some tissues, organs, and cells. This has helped to advance several of today’s bioelectric impedance applications, like Electrical Impedance Tomography (EIT), Electrical impedance spectroscopy (EIS). For calculating bioelectric impedance it is very important to design low power Analog Front end consisting of Op-amp and ADC. In this paper, a low supply voltage based FinFET operational amplifier and its characteristics are studied and designed by using Cadence 18nm FinFET technology. The standard characteristics of the op-amp like gain, bandwidth, unity gain bandwidth product, settling time and so on are distinguished with the existing architectures. The suggested FinFET-based amplifiers are having a greater performance at a reduced voltage than conventional two-stage Op-amps. In this work, supply voltage is provided as 0.8V. The circuit consumes a power of 35 μW, provides a gain of 83 dB and unity gain repeat of 10 MHz with a phase edge of 70 degrees. The difference between the suggested architecture and standard two stage CMOS Op-amp shows that figure of Merit for proposed circuit is improved to 1.1pj.

Keywords: Op-Amp, FINFET, ADC, DAC

1. INTRODUCTION
In the current digital market [1], the trend towards the development of bio-medical devices with portable batteries has recently increased. This phenomenon is because of progress and advancement in scaling of VLSI technology leading to more analog and digital circuit (ADC) creation in deep sub-micron size [2]. This condition has its own advantages where, at lower voltage supply, the circuit can be operated with lower power consumption. But most analog and digital electronic circuits suffered performance degradation due to technology scaling short-channel effects (SCEs). Bio-potential identification of signals in the medical world is the most common and dependable way for medical practitioners to diagnose their patient’s medical conditions. Many bio-potential signal detections such as, electromyography, electroencephalography and electrocardiography are recognized in the medical world.

EMG, EMG and ECG are the typical bio-potential signals provided by the human body. There are common characteristics of these bio-potential. Signals; amplitude of low frequency range and low voltage. Table 1 shows the range of frequencies and voltage amplitude of the specified bio-potential signal [3]. The observation and recording of bio potential signal is of importance in medical
diagnosis and contemporary clinical practices require routine recording of these signals. Patients are generally linked to lengthy recording instruments in order to obtain signals from the body for diagnosis purposes. This impacts their mobility and creates overall unease. As a consequence, acquisition time decreases and avoids constant patient monitoring affecting the overall diagnosis of diseases.

Bioelectric impedances have been found to correlate with a number of biological phenomena in some tissues, organs, and cells. This has helped to advance several of today's bioelectric impedance applications, like Electrical Impedance Tomography (EIT), Electrical impedance spectroscopy (EIS) [4].

Scientists are currently investigating a variety of different applications, including glucose control, breast cancer control, foot sole blood perfusion, and instant blood pressure [5][8]. Researchers also started studying implantable bio-impedance analyzers, which would require minimally invasive data monitoring around the clock. Bio-impedance correlations and different biological processes can then be tracked with greater care. One group working with regenerative tissue is seeking to repair an existing wound from the infarction. For example, if a patient suffers from heart attack, the cells that are present in the left ventricle of the heart may be deprived of oxygen and they will ultimately die. As seen in Figure 1 this causes the left ventricle to shrink.

Figure 1. On the left side normal heart and on right side a heart after a heart stroke [9].

Side effects include toxicity to the blood pressure, heart failure and inevitably death [9]. One cardiac repair mechanism to prevent this from happening is by using stem cells to reinforce the post-infarction scar. In order to make them more flexible, stem cells can regenerate scar tissues and improve the functioning of the left ventricle. For this function, an implantable bio-impedance control apparatus should be built. The device will calculate impedance at different frequencies and the current source will inject the required current into the body at one of the required frequencies and measure and then evaluate the resulting voltage drop. The ADC must perform impedance calculation and digitization. Different types of ADCs may be used depending upon the type of frequency measurement. Nevertheless, a reconfigurable converter should be considered because it might give the other converters a number of advantages. For a bio-impedance monitoring system it would be highly useful to provide a reconfigurable ADC with the ability to detect the bio-impedance at high frequencies, as well as the ability to adjust bias currents at lower frequency measurements. With enhanced power efficiency, this allows monitoring of the wide range of useful bio-impedance data.
Table 1 Various characteristics of the Bio-Potential Signals [3]

<table>
<thead>
<tr>
<th>Organ</th>
<th>Name of the Bio-potential signal</th>
<th>Frequency (Hz)</th>
<th>Amplitude Value(mV)</th>
</tr>
</thead>
<tbody>
<tr>
<td>Muscles</td>
<td>EMG</td>
<td>Up to 2K</td>
<td>0.1 to 5</td>
</tr>
<tr>
<td>Heart</td>
<td>ECG</td>
<td>0.01 to 250</td>
<td>0.5 to 4</td>
</tr>
<tr>
<td>Brain</td>
<td>EEG</td>
<td>0.5 to 150</td>
<td>0.0005 to 0.3</td>
</tr>
</tbody>
</table>

Figure 2. A typical ECG/EEG monitoring system.

Their objective is to develop a bio power recording system that is comfortable, has long term energy independence and has high signal quality and can be configured to help in several biomedical applications. Their goals are to ensure that the mini-ambulatory bio potential procurement systems have a low noise and very low-power requirement. This is necessary for a comprehensive study on the design of such interfaces and the ultimate purpose. The block diagram of Analog Front End of the ECG/EMG recording system is shown in the figure 2. It comprises of the electric release (ESD) and the defibrillator protection (INAMP), the analog-to-digital (ADC), and then a wireless transceiver. With the help of the ESD protective circuit, defibrillator safety is implemented in modern ECG/EMG systems before the analog front end, to improve patient safety, the user and the device itself in the event of discharges or emergencies. The ADC digitizes the signal before it is transferred next after the instrumentation amplifier. A 10-bit ADC is needed for ECGs with a dynamic range of up to 60 dB. The consecutive ADC approximation is a useful option for this ADC resolution and low-frequency sampling. This can be done when a fairly tiny quantity of energy is dissipated. Many components such as operational amplifier, LPF, and ADC are incorporated in the detection system [10]. Operational amplification is known as a bio amplifier in the bio potential detection system where it acts to amplify the minute amplitude of the signal to a higher and appropriate amplitude rate so that the ECG/EMG signal can be interpreted by the next components in the detection system. Because bio amplifier is the first and main building block in the bio potential signal detection system, it will consume a great deal of power during its operation and increase the total power consumption of the detection system itself [11][12].

The Operational amplifier is the main important block of the Instrumentation Amplifier. It is the first block in the design of Analog Front End (AFE) system, which is responsible for the acquisition and amplification of bio potential signal. As per the necessary determinations, a few designs of operational amplifiers are planned. Operational amplifiers are commonly known to be voltage amplifiers, which are mainly used for achieving elevated gains through the use of differential information sources. The gain is between 50 and 60 dB more often than not. Due to the transistor channel length reduction and lower supply voltages of the present day CMOS technology, designing of a operational amplifier is the challenging task for the designing engineers. When we scale down the size of MOSFET, the channel length of the device shrinks and this proximity between the source and the drain decreases the influence of the gate voltage on the potential transmission and current flow in the channel, which degrades the output of the device. It induces structural instability when we scale MOSFET down to nanometres. This is mainly due to short channel effects (SCEs) which
play a key role in deciding the output of scaled devices. While output degrades with a decrease in channel length as the device dimension shrinks, it is increasingly difficult to perform basic device manufacturing steps such as lithography, interconnecting and processing. As the dimension of the system becomes smaller, the circuit becomes denser and more complex.

1.1 Errors during the MOSFET Downscaling

Generally referred to as short channel effects is the class of effects that modify device behaviour resulting from device miniaturization. It leads to an increase in the current of leakage between the drain source and decreases the current ratio of ON-state to OFF. In particular, it is possible to distinguish the short channel effects [14-20].

a. Drain Induced Barrier Lowering (DIBL):

The potential barrier is controlled by both Vgs and Vgs in small MOSFET geometry. When Vds increases, the barrier of the electron or the holes in the source decreases so that they can pass from the source and drain where the voltage of the gate remains unchanged. The potential barrier to the channel decreases, contributing to DIBL. Reducing the potential barrier ultimately enables the electron to pass between the source and the drain, even if it is VgsVth. When the area of depletion region surrounding the drain enters the source, so that the two layers of depletion layers overlap, punching occurs. Gate loses current flow control via MOSFET and becomes as good as redundant. With thinner oxide, larger substrate doping, shallower junctions and obliviously longer channel, punching through can be minimized.

b. Hot Electron Effect:

If carriers gain high energy at an effective temperature higher than the temperature of the lattice, it is said that they are hot. Such cold electrons are produced when MOSFET operates in linear or saturation mode in the inverted channel region. These hot electrons cannot pass their energies to the lattice atoms quickly enough. The key issues that arise as a result of hot carriers are parasitic gate currents, weakening drain current, increasing transconductance, and rising threshold voltage over time. The use of graded drain profile decreases the generation of hot carriers. The technique is used in floating gate devices to raise the threshold by trapping electrons in the floating gate. The drain is doped slightly through this process, resulting in less electrical field produced for the carrier.

c. Parasitic resistance and Capacity:

Due to the reduced parasitic resistance of the transistor dimensions and the capacity is both unfavourably scaled and diminished. As a consequence, the effect of parasitic elements on the current is significantly increasing. Such parasite elements should reduce the transistor scaling efficiency.

d. Velocity saturation:

The velocity is directly proportional to the electrical field up to a certain point. But the point's velocity is saturated and does not raise the electrical field. It lowers saturation mode transconductivity.
c. Heat dissipation:

MOSFETs in the resistive portion release energy in the form of heat. Hot spots are generated on the circuit if this heat is not dissipated properly, which ultimately leads to system malfunction.

As the devices continue to shrink, there is an increasing problem with conventional MOSFETs [1]. One problem's solution leads to another. Short channel effects like VT roll off, drain-induced barrier lowering (DIBL), increasing the current of leakage, etc. To solve these short channel effects issues, such as double gate, FinFET, Tri-gate, Fore-gate, all-around gate, and so on, a lot of MOSFET has been implemented. It needs new architectural structures to design and implement operational amplifiers, as noted above, an increase in demand for low-power applications and accuracy. In addition, structuring a high-speed and high-gain operational amplifier is essential in high-precision devices. In addition, with FinFET to better understand multi-gate devices, we will present a high-gain and low-control voltage operational amplifier and the advantages of the framework suggested to enhance basic amplifier parameters including gain and bandwidth. In the section 2, Introduction to FINFET devices is presented, in the section 3; various characteristics of FinFET are presented. Methodology regarding the proposed technique is studied in section 4. The proposed Operational Amplifier and its simulation is discussed in the section 5 and 6 respectively followed by Conclusion in section 7.

2. FINFET DEVICES

It is difficult to fabricate planar DG MOSFETs. The challenges are to align the top and the bottom gates and to make the bottom gate of a low resistance contact width. The FinFET is a relatively easy to manufacture alternatively to the DG MOSFET. Figure 3 shows the Fin-FET structure with the entire fin cuts. In order to produce a Fin-FET double gate, the top oxide is much thicker than the side oxides in order to efficiently inactivate the top gate [21-24].

![FinFET structure with a perspective over the entire fin](image)

The width is obviously \( W = 2H_{\text{fin}} + W_{\text{fin}} \) for a FinFET. \( W_{\text{fin}} \) must be small enough in order to have a lower short channel effects. In addition, in a DG FinFET, \( W \) is safe at around \( 2H_{\text{fin}} \). Thus, almost the literature on compact model development for the DG MOSFET can be implemented, with a small adjustment \( n \) parameter (\( H_{\text{fin}} \)). The physical aspects of FinFET are therefore larger than the DG MOSFET. This area is technologically inevitable because a steeper lateral doping gradient is not expected from a heavily doped source/drain, and finishes with a slightly doped channel area (a slightly doped bodies are preferred since random doping fluctuations and mobility degradation impacts can be reduced). As such, FinFETs are usually resistant to a comparatively big number of parasites [25-27].
3. CHARACTERISTICS OF FIN FET

Now we are talking about the electrostatic characteristic of FinFET (Current-voltage).

The unique characteristic of FinFET is that the gate is formed by a conductive channel enclosed by thin "fin" silicon. The thickness of the fin is determined from the source to the drain in the direction that defines the device's effective channel width [28][29]. The gate electrode is wrapped around the channel so that multiple gate electrodes can be formed on each side, resulting in reduced leakage currents and increased drive current. For FinFET, a self-aligned double gate controls the vertical si fin.

Linear Region: It is the region where $I_{ds}$ is increased linearly with $V_{ds}$, for a given $V_g > V_{th}$ For the first approximation, $I_{ds}$ is given in the linear region as

$$I_{ds} = \frac{2\mu C_{ox} W}{L} \left(V_g - 2V_{th} - \frac{V_{ds}}{2}\right) V_{ds} \quad (1)$$

Where $V_{th}$ is the threshold voltage is called as carrier mobility in the inversion region, i.e. the channel, $C_{ox}$ is the gate oxide capacitance per unit area, $W / L$ is the device width to length ratio.

Saturation Region: In this region, $I_{ds}$ is becoming constant even though $V_{ds}$ is increasing. Once again, for the first rough calculation, the $I_{ds}$ are in the saturation region given by

$$I_{ds} = \frac{\mu C_{ox} W}{L} \left(V_g - V_{th}\right)^2, \quad m=1+3(tox/xd) \quad (2)$$

$x_d$ is the thickness of the depletion layer and tox is the thickness of the oxide showing that $I_{ds}$ does not depend on $V_{ds}$.

Cut-Off Region: In this region $V_g < V_{th}$ so that there is no channel between the source and the drain resulting in $I_{ds}$=0. In fact, for $V_g < V_{th}$, the sub threshold current flows is the exponential decay current.

Low concentration of electrons results in high electrical field along the channel and, as a consequence, sub-threshold current is primarily due to carrier diffusion. This current of this region is approximated as

$$I_{ds} = \frac{\mu W}{L} K T n_i t S i e^{q(V_g - \Delta \phi) / kT} \left(1 - e^{q(V_{ds}) / kT}\right) \quad (3)$$

$\Delta \Delta$ is the difference between the function of the gate electrode and the almost intruded silicon skin.

4. METHODOLOGY

The following section discusses the details of the methodology which will be used to implement the proposed technique [16-20].

The flow chart shown in the figure 4 demonstrates the method followed for the designing of the opamp in biomedical applications.
5. PROPOSED OP-AMP

FinFET is one of the most encouraging advancements to structure beneath 50 nm. So as to stay aware of innovation, transistor sizes must be decreased which prompts a few deficiencies in the presentation of the transistor FinFET can address a substantial amount of these problems in order to enhance the performance of the circuit. When trying to decrease the size of FinFET transistors, it offers a large enhancement in comparison to standard single gate CMOS structures in simple circuit configurations. Figure 5 shows the square outline of an amplifier with differential information. The two stage operational amplifiers consist of four main sections as depicted in the block diagram in Figure 5. The two operational amplifiers include: the information of difference amplifier, an additional circuit for increased gain, biasing circuit and the offset controllable circuit. Because the circuit load is capacitive, the amplifiers do not require the additional stage. The differential input amplifier amplifies the small differences from the inputs of amplifier. The compensation circuit is mainly used in op-amp for the purpose of stabilization and the bias circuit is tasked with offering the amplifier circuit bias voltages [8-12]. A proposed two stage FinFET based operational amplifier with compensation capacitor Cc circuits demonstrated in Figure 6 and the drawn schematic using virtuoso schematic editor is shown in Figure 7. Figure 5 presents a proposed two stage operational amplifier with a capacitor, Cc and Figure 5 demonstrates the diagram of the proposed operational amplifier circuit drafted with a virtuoso schematic editor. The later stage of differential amplifier is typically used as a simple fundamental common source amplifier to have the most extreme swing in the yield. The amplifier consists of the Cascode stages of current to voltage (I to V) converter and voltage to current (V to I) (Allen and Holberg) [32]. The primary phase consists of differential amplifiers which are attached to mirror loads for recovering differential voltage. This is obviously only a differential voltage amplifier [33-38].

Figure 4. Flow Chart of the Methodology
Figure 5. Block diagram of two-stage op-amp

![Block Diagram of Two-Stage Op-Amp](image)

Figure 6. FinFET op-amp proposed for two-stage offset circuit

First stage gain \( G_1 = \frac{g_{m1}}{g_{ds2} + g_{ds4}} = \frac{2g_{m1}}{I_s(\lambda_2 + \lambda_4)} \) \hspace{1cm} (4)

Second stage gain \( G_2 = \frac{g_{m6}}{g_{ds6} + g_{ds7}} = \frac{2g_{m6}}{I_s(\lambda_6 + \lambda_7)} \) \hspace{1cm} (5)

Gain bandwidth product \( GBW = \frac{g_{m1}}{C_C} \) \hspace{1cm} (6)

The op-amp having a current source which is designed using transistors M9 and M10 as shown in Figure 3 the current driven this current source is 20μA. The designer can notice a very balanced differential input and a very large gain from this operation amplifier (op-amp). This parallels the comparators’ features and applications in various fields.

The biasing current is determined based on the region of working of the transistors in the circuit of Op-amp. For low power operation of the transistors, the transistors are made to operate in the inversion region i.e. in weak inversion region or moderate inversion region. To operate in the weak inversion or moderate inversion regions, the gate voltage \( V_g \) should be just below the threshold voltage \( V_t \) of the transistor. In this region very low quantity of currents will be flowing and that currents are considered for the biasing of the circuits.

In the Proposed circuit, the first stage transistors M1, M2 forms the input differential stage which is used to acquire the difference input voltage of two signals. The transistors M9-M10 form the current mirrors for biasing the circuit. These transistors provide the required biasing for the circuit based on the dimensions of the transistors. The transistors M7-M8 also form the current mirror circuits.
Figure 7. Proposed architecture of two-stage FinFET op-amp schematic circuit along with compensation circuit technique

The mirroring factor for the M7-M8 should be in the ratio of K: 1 when compared with M9-M10 because more current is provided at the output stage resulting in the high gain.

The transistor M5-M6 forms the second stage of the amplifier, which is a gain stage. The transistors in this stage form a common source amplifier that is used to amplify the gain of the stage 1.

During the design, the dimensions of the transistors are kept in the mind. The transistor dimensions allow the required current to flow in the transistors.

The Operational amplifier enables the bio potential signals to be processed by the following blocks, by amplifying them and recording the signal received with a small noise and interference. The ECG/EEG signal is typically between 0.1mV and 5mV and very small (0.1-100Hz) as stated earlier. The dominant MOS transistor noise (1/f) will, due to the nature of the signal, significantly restrict the detectable minimum signal unless addressed. In addition, the skin electrode interface has a issue of DC offset produced. Transistors also demonstrate low input DC offset efficiency. Because of this input referred noise the acquired low voltage low frequency signal may be lost. To overcome chopper stabilization techniques or auto zeroing techniques must be used.

Moreover, the input referred noise is caused due to the presence of flicker noise and thermal noise. By increasing the area of the transistor, flicker noise can be minimized. Also the thermal noise can be minimized by increasing the transconductance of the input transistors. To do this the area of the input transistors must be increased; therefore the input transistors width will be increased to overcome the effects of the noises present.

6. SIMULATION RESULTS

The low power operational amplifier has been achieved desired specifications. This is designed using 18nm Fin-FET technology. The length of all the transistors is chosen to be 18nm. But widths are varied as per the requirements discussed the section 5. This complete op-amp can operate with 0.8V supply voltage. The proposed architecture of Op-amp shown in the figure 8, consumes power of 35uW; the primary purpose of this op-amp design is to test a function that can generate up to an 83dB gain as shown in Figure6. In this brief, the total work is carried out in Cadence EDA tools.
Figure 8. DC gain of the proposed op-amp

Table 2: Summary of the Proposed Comparator Performance

<table>
<thead>
<tr>
<th>S.No</th>
<th>Parameter</th>
<th>Value</th>
</tr>
</thead>
<tbody>
<tr>
<td>1</td>
<td>Technology</td>
<td>18nm Fin-FET</td>
</tr>
<tr>
<td>2</td>
<td>Supply voltage</td>
<td>0.8V</td>
</tr>
<tr>
<td>3</td>
<td>Delay</td>
<td>1ns</td>
</tr>
<tr>
<td>4</td>
<td>Power</td>
<td>35uW</td>
</tr>
<tr>
<td>5</td>
<td>DC gain</td>
<td>83dB</td>
</tr>
</tbody>
</table>

Table 3: Comparison with Existing Architectures

<table>
<thead>
<tr>
<th>Parameter</th>
<th>Ref [39]</th>
<th>Ref [40]</th>
<th>Ref [41]</th>
<th>Proposed</th>
</tr>
</thead>
<tbody>
<tr>
<td>Technology</td>
<td>Fin FET</td>
<td>Planar MOS</td>
<td>Fin FET</td>
<td>Fin FET</td>
</tr>
<tr>
<td></td>
<td>100nm</td>
<td>FET 90nm</td>
<td>32nm</td>
<td>18nm</td>
</tr>
<tr>
<td>DC Gain(db)</td>
<td>61</td>
<td>28.99</td>
<td>49</td>
<td>83</td>
</tr>
<tr>
<td>Power</td>
<td>90</td>
<td>314</td>
<td>234</td>
<td>35</td>
</tr>
<tr>
<td>Dissipation(uW)</td>
<td></td>
<td></td>
<td></td>
<td></td>
</tr>
</tbody>
</table>

The Table 2. Shows summary of the achieved performance characteristics of the proposed operational amplifier, such as delay, gain, power consumption and operating voltage. From the table it is noted that, the proposed architecture of op-amp has good gain of about 80db with less delay. From the Table 3, it is noted that the proposed architecture of Op-amp consumes less power and provides good gain when compared with few other existing architectures.
7. CONCLUSION

In this paper a low voltage low power operational amplifier is proposed. This is designed using 18nm Fin-FET technology and simulated using Cadence Virtuoso. The power and timing analysis done and the simulation results are shows the improvement in the design of a novel operational amplifier, performance, and also other references like power, time delay.

REFERENCES


